

ABSTRACT OF THE DISCLOSURE

A testing method for an electronic component in which a predetermined load is set, which is determined by a burn-in temperature, a burn-in voltage, and a burn-in period of time, and burn-in of an electronic component is carried out in such a manner that a load equal to the predetermined load is applied to the electronic component, with the method including a first step of placing an electronic component having a negative resistance-temperature characteristic in a heating atmosphere so that the temperature of the electronic component reaches a predetermined temperature which is lower than the burn-in temperature, a second step of supplying constant current to flow through the electronic component so that the predetermined temperature of the electronic component is increased to the burn-in temperature, and a third step of comparing the voltage actually applied to the electronic component to the burn-in voltage, correcting the burn-in time-period based on the comparison to determine a corrected burn-in time-period, and applying constant current to flow through the electronic component based on the corrected burn-in time-period.